

100V N-Channel Enhancement Mode MOSFET

Description

The AP100N10NF uses advanced **APM-SGT II** technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

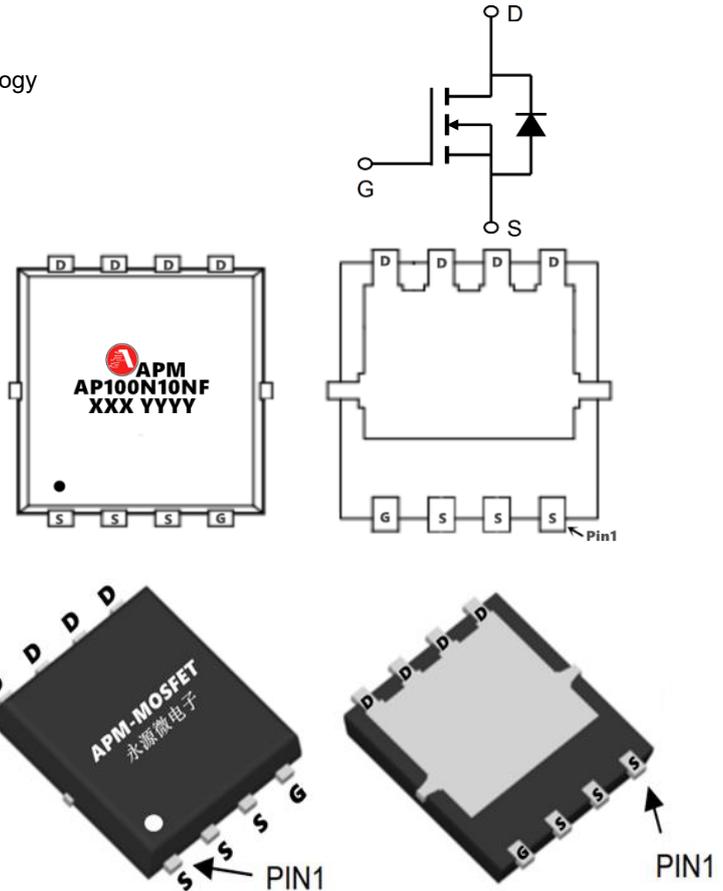
$V_{DS} = 100V$ $I_D = 100A$

$R_{DS(ON)} < 5.5m\Omega$ @ $V_{GS}=10V$ (Type: **4.3m Ω**)

Application

BLDC

LED Backlighting



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP100N10NF	PDFN5*6-8L	AP100N10NF XXX YYYY	5000

Absolute Maximum Ratings ($T_C=25^\circ C$ unless otherwise noted)

Symbol	Parameter	Max.	Units
V_{DSS}	Drain-Source Voltage	100	V
V_{GSS}	Gate-Source Voltage	± 20	V
$I_D@T_C=25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V_1$	100	A
$I_D@T_C=100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V_1$	68	A
I_{DM}	Pulsed Drain Current	417	A
E_{AS}	Single Pulsed Avalanche Energy	245	mJ
I_{AS}	Avalanche Current	42	A
$PD@T_C=25^\circ C$	Power Dissipation	24	W
T_J TSTG	Operating Junction Temperature Range	-55 to 150	$^\circ C$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹	25	$^\circ C/W$
$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.0	$^\circ C/W$

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Electrical Characteristics ($T_J=25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
VDSS	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = 250\mu A$	100	103	-	V
IGSS	Gate-body Leakage current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	± 100	nA
IDSS	Zero Gate Voltage Drain Current $T_J=25^\circ\text{C}$	$V_{DS} = 100V, V_{GS} = 0V$	-	-	1	μA
IDSS	Zero Gate Voltage Drain Current $T_J=100^\circ\text{C}$		-	-	100	
VGS(th)	Gate-Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\mu A$	2.0	2.9	4.0	V
RDS(on)	Drain-Source on-Resistance ²	$V_{GS} = 10V, I_D = 20A$	-	4.3	5.5	m Ω
Ciss	Input Capacitance	$V_{DS} = 50V, V_{GS} = 0V, f = 1\text{MHz}$	-	2816	-	pF
Coss	Output Capacitance		-	614	-	
Crss	Reverse Transfer Capacitance		-	7.4	-	
Rg	Gate Resistance	$V_{GS} = 0V, V_{DS} = 0V, f = 1\text{MHz}$	-	2.4	-	Ω
Qg	Total Gate Charge	$V_{GS} = 10V, V_{DS} = 50V, I_D = 20A$	-	42	-	nC
Qgs	Gate-Source Charge		-	9.7	-	
Qgd	Gate-Drain Charge		-	10.6	-	
td(on)	Turn-on Delay Time	$V_{GS} = 10V, V_{DS} = 50V, R_G = 3\Omega, I_D = 20A$	-	13	-	ns
tr	Rise Time		-	25	-	
td(off)	Turn-off Delay Time		-	43	-	
tf	Fall Time		-	37	-	
VSD	Diode Forward Voltage ²	$I_F = 20A, V_{GS} = 0V$	-	-	1.2	V
IS	Continuous Source Current ^{1,5}	$V_G = V_D = 0V$, Force Current	-	-	167	A
trr	Body Diode Reverse Recovery Time	$I_F = 20A, di/dt = 100A/\mu s$	-	60	-	ns
Qrr	Body Diode Reverse Recovery Charge		-	61	-	nC

Note :

- 1、The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
- 2、The data tested by pulsed , pulse width $\cong 300\mu s$, duty cycle $\cong 2\%$
- 3、The EAS data shows Max. rating . The test condition is $V_{DD} = 72V, V_{GS} = 10V, L = 0.1mH, I_{AS} = 42A$
- 4、The power dissipation is limited by 150°C junction temperature
- 5、The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Typical Characteristics

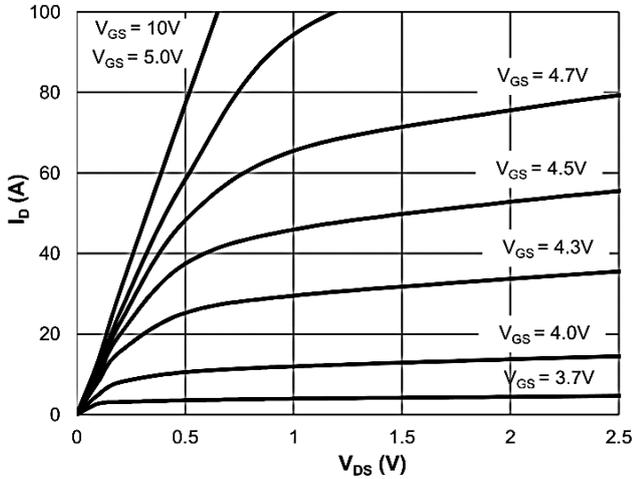


Figure 1: Saturation Characteristics

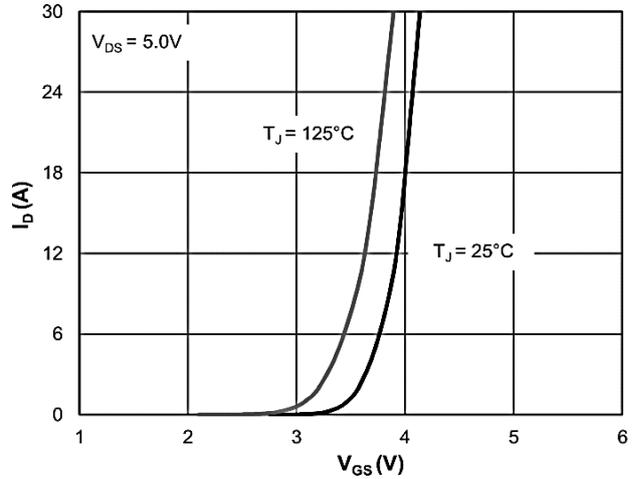


Figure 2: Transfer Characteristics

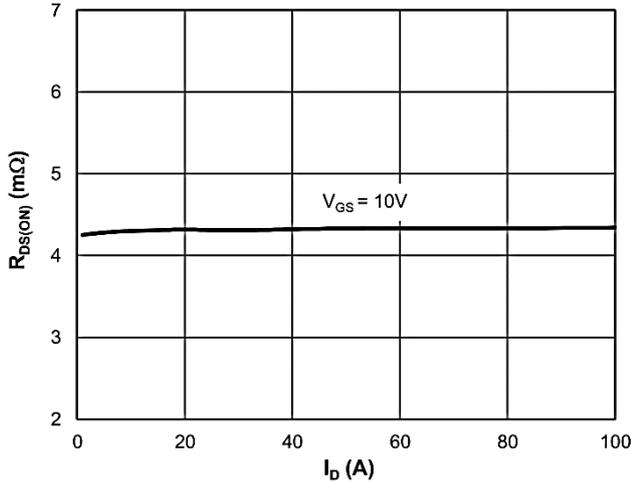


Figure 3: $R_{DS(ON)}$ vs. Drain Current

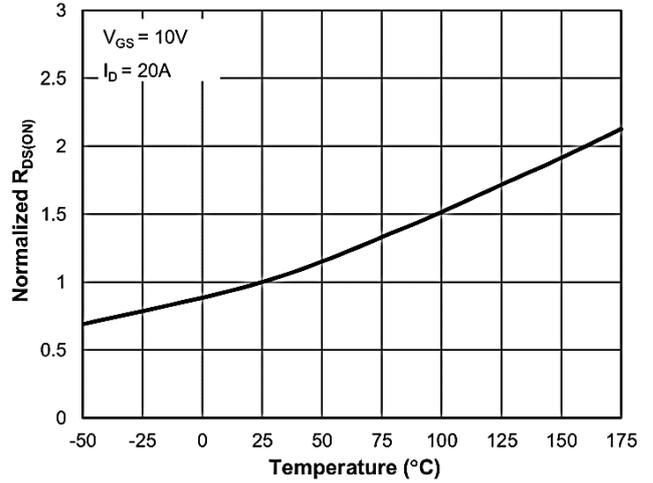


Figure 4: $R_{DS(ON)}$ vs. Junction Temperature

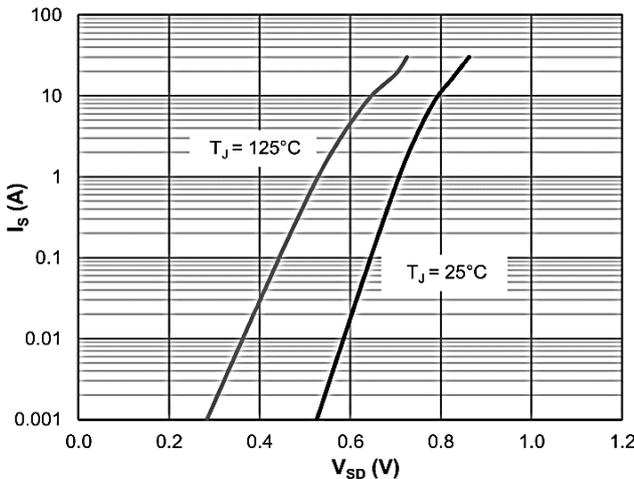


Figure 5: Body-Diode Characteristics

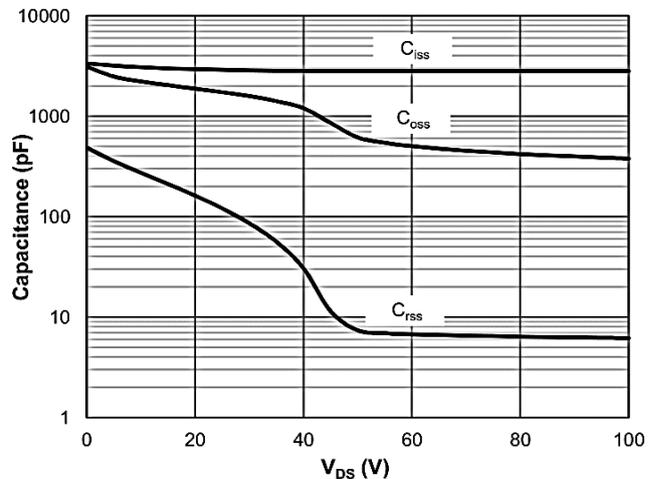


Figure 6: Capacitance Characteristics

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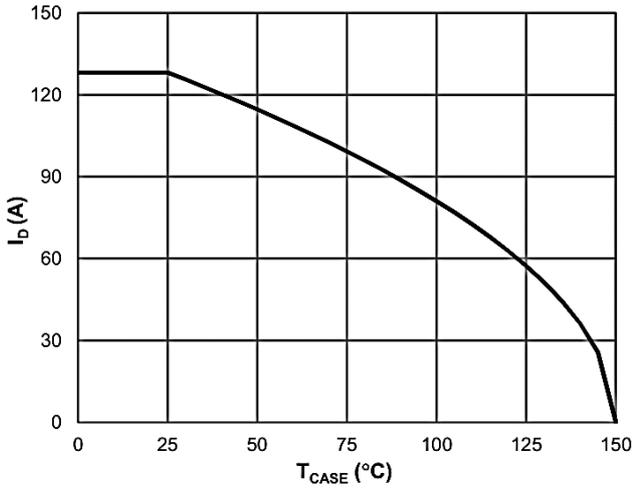


Figure 7: Current De-rating

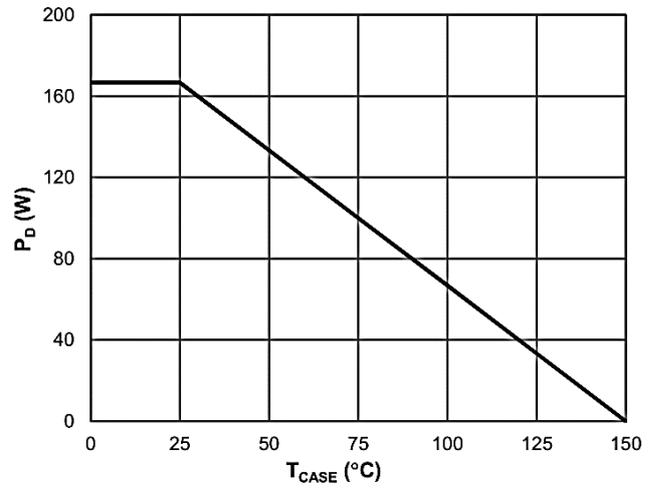


Figure 8: Power De-rating

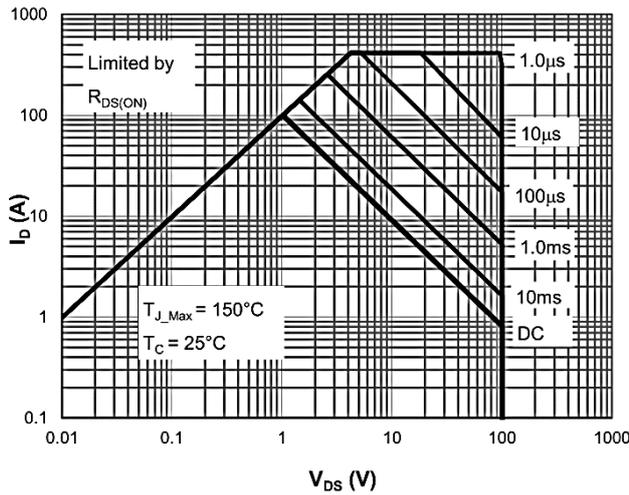


Figure 9: Maximum Safe Operating Area

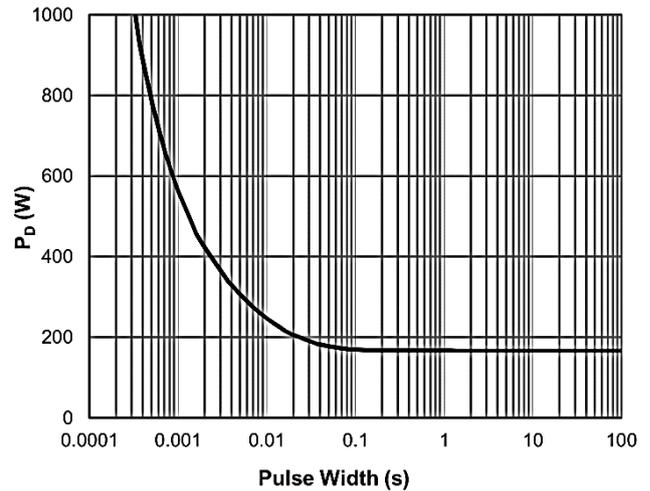


Figure 10: Single Pulse Power Rating, Junction-to-Case

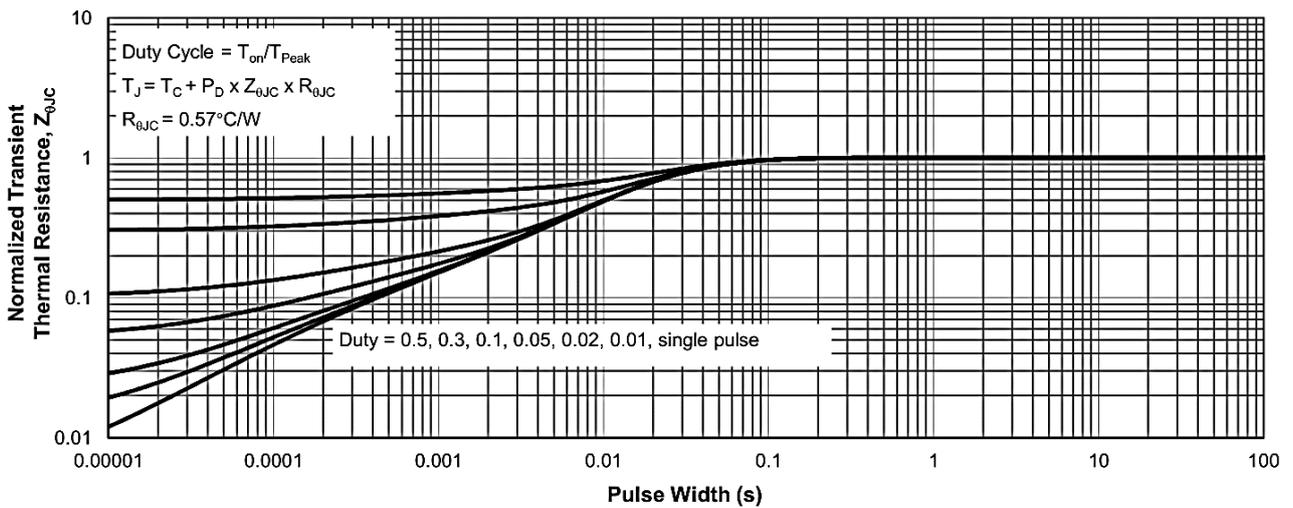
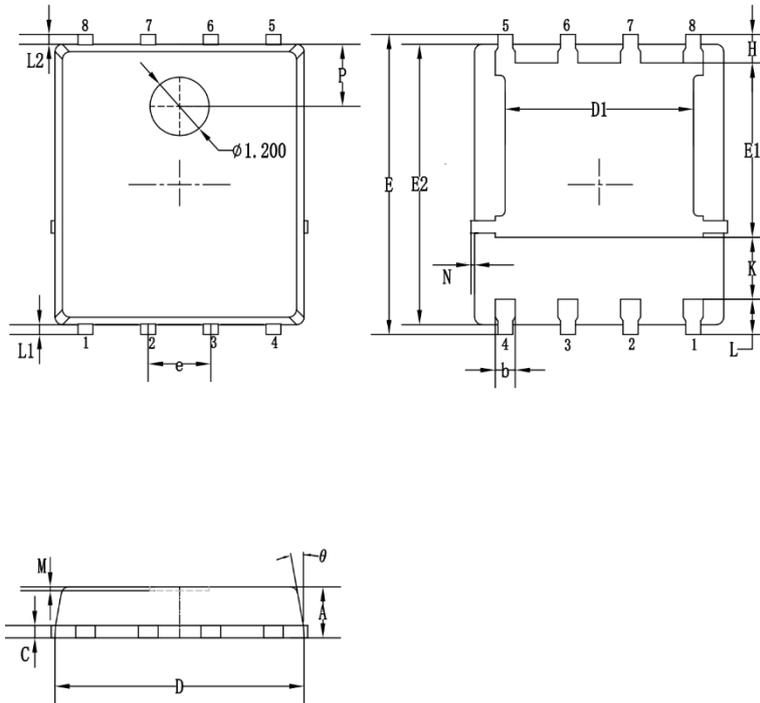


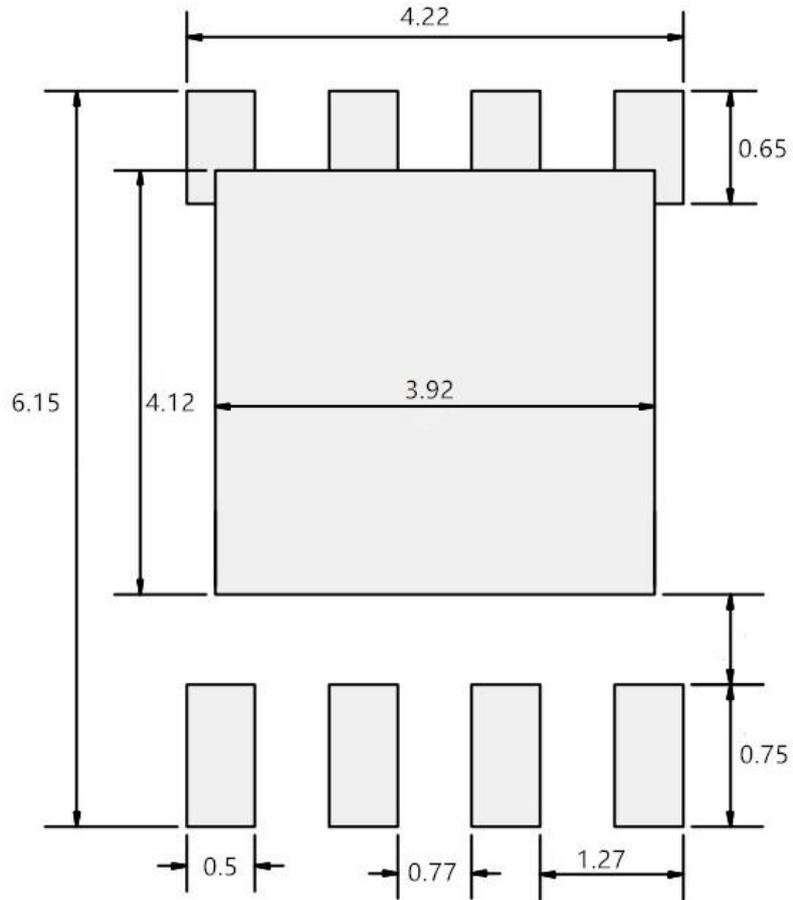
Figure 11: Normalized Maximum Transient Thermal Impedance

Package Mechanical Data-PDFN5*6-8L Single



Symbol	Dim in mm		
	Min	Typ	Max
A	0.9	1.05	1.2
b	0.3	0.4	0.5
C	0.2	0.25	0.35
D	4.9	5.05	5.2
D1	3.72	3.82	4.12
E	5.9	6.1	6.3
E1	3.3	3.5	3.7
E2	5.6	5.75	5.9
e	1.27BSC		
H	0.48	0.58	0.7
K	1.14	1.27	1.4
L	0.54	0.74	0.84
L1/L2	0.1	0.2	0.3
θ	8°	10°	12°
M	0.08REF		
N	0		0.15
P	1.28REF		

Recommended Minimum Pads



Dimensions in (mm)

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Edition	Date	Change
REV1.0	2023/3/31	Initial release

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